

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10009579	DE LEIJ ET AL.
	Examiner	Art Unit
	Qian Ph.D., Celine X	1636

SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES

Search Notes	Date	Examiner
Search updated.	9/15/06	CQ
Search updated	5/24/2007	CQ
Search updated	10/23/2007	CQ
Search updated	4/24/2008	CQ

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
	Interference search performed by STIC in interference database(see score)	4/24/2008	CQ